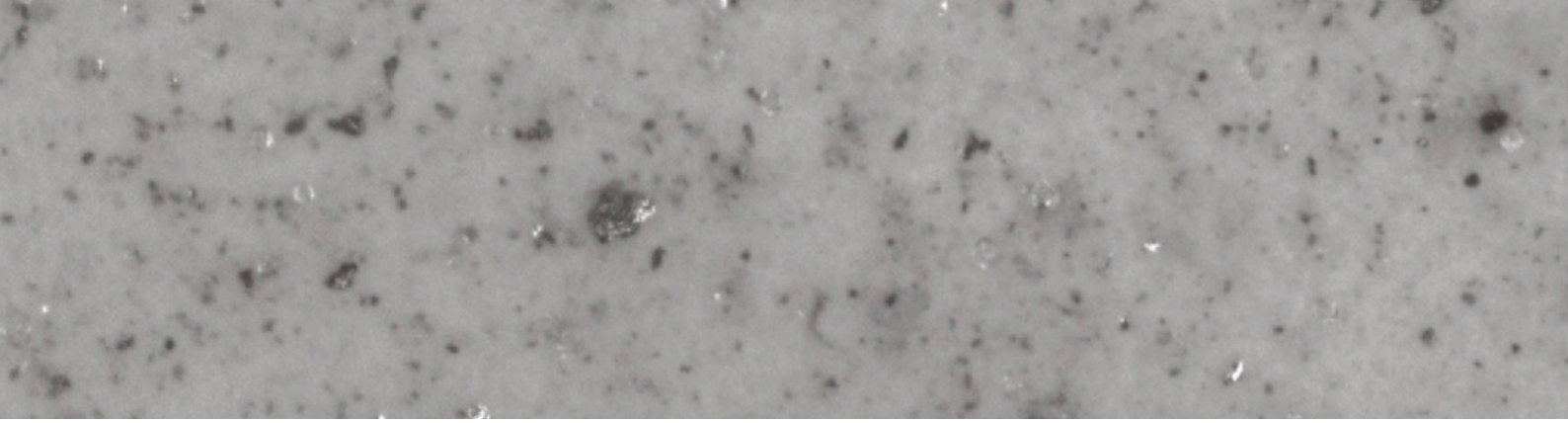
From Eye to Insight

Leica
MICROSYSTEMS

Automotive and Other Industries

FAST AND EASY PARTICLE COUNTING ON FILTERS

The Cleanliness Expert Analysis Software

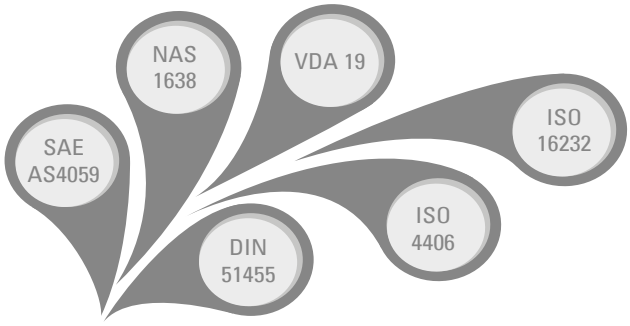


Fast and easy particle counting on filters

LAS X Cleanliness Expert analysis software provides many advantages to speed up and ease your inspection process in technical cleanliness. Cleanliness Expert software is an easy-to-use, optimal solution to provide you with reliable, repeatable analysis results specific to your application needs.

Manage more than one sample

Analyze more than one sample at the same time, improve your workflow efficiency and simplify your process with automated particle analysis. Combine for example multiple filter samples from one filtration process into a single batch for analysis and assign different settings for particle classification for each filter. Generate reports easily to share your results.

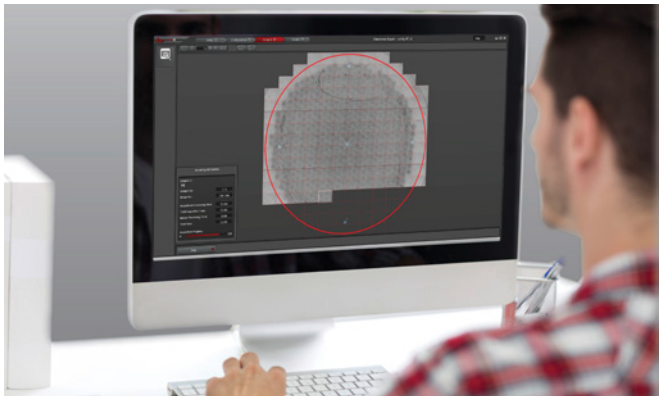


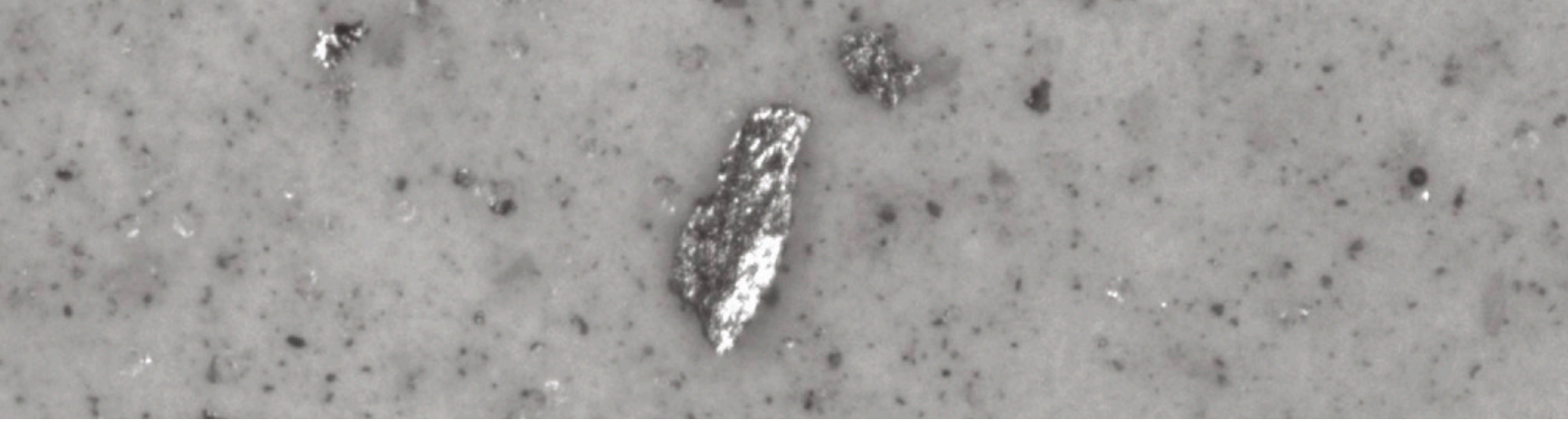
Meet or exceed standards

Inspection is an important step in product safety, and is key for reliability and conformity to standards. Documenting the cleanliness of your parts and components is essential in order to attain the necessary certifications.

Choose Cleanliness Expert software:

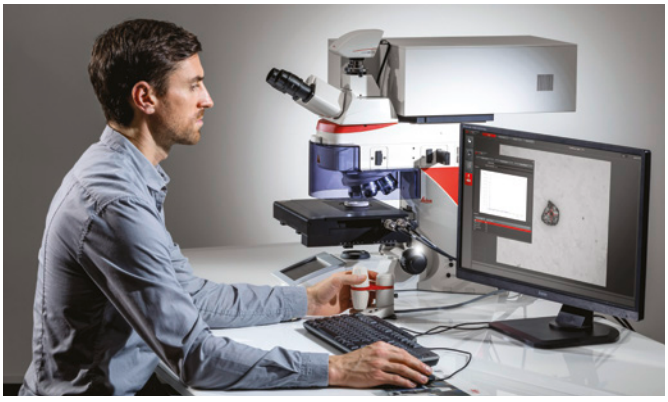
- Determine the full damage potential of the particle by measuring height, not just the length and width
- Acquire reliable and reproducible results with the store and recall function
- Include individual requirements
- Analyze round or rectangular samples
- Automatic differentiation between reflective and non-reflective particles
- Autofocus and detection algorithms for user independent analysis
- User interface is configurable to specific needs

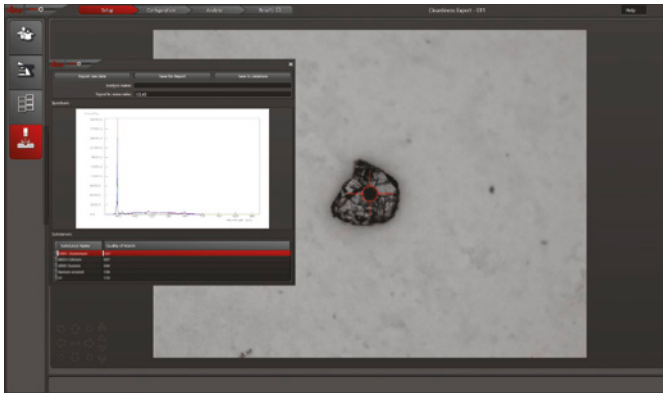




Identify the source of contamination

Imagine if you could combine visual and chemical inspection in a single workflow solution to help you find the source of contamination. Cleanliness Expert software combined with the exclusive new Laser Induced Breakdown Spectroscopy (LIBS) system provides you with a flexible 2-in-1 analysis solution. Knowing more about the contamination quickly and easily gives your business an advantage when making decisions.



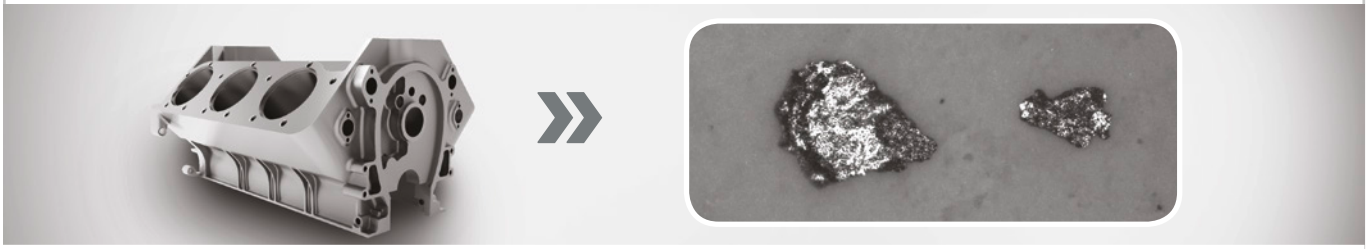


Leica MICROSYSTEMS

PALL Pall Corporation

Cleanliness analysis from A to Z:

A thorough cleaning process of parts is essential to successfully carry out the particle analysis with an optical evaluation system. Instruments from several suppliers are used to perform these tasks. Now Leica Microsystems and Pall Corporation have joined efforts to offer a unique, complete integrated workflow solution for component cleanliness from one source.



Extraction & Filtration › Detect, Count & Classify › Relocate & Check › React

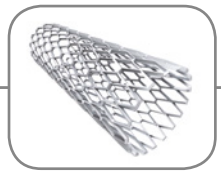
Cleanliness Expert software from Leica Microsystems is used in various fields


Automotive


Transportation


Fuels & Lubricants


Parts & Components


Medical Devices


Pharmaceutical Manufacturing

Choose the solution or system that meets your requirements

Large particle solution:	**Small particle solution:**	**Automated small particle solution:**
DMS1000 microscope with Cleanliness Expert software	**DM2700 M microscope** with digital camera and Cleanliness Expert software	**DM4/6 M microscope** with digital camera and Cleanliness Expert software
Recommended for quantify particles down to 25µm Smaller particles on request	Recommended for quantify particles down to 5µm Smaller particles on request	Recommended for quantify particles down to 5µm Smaller particles on request
Manual intervention required to insert polarizer for metallic/non-metallic particle recognition	Manual intervention required to insert polarizer for metallic/non-metallic particle recognition	Fully-automated recognition of metallic/non-metallic particles
Camera, classification and report setting stored in configuration file	Camera, classification and report setting stored in configuration file	All camera, illumination, contrast, and classification settings are stored in configuration file and applied automatically
Measure particles in XY	Measure particles in XYZ	Measure particles in XYZ
		Optimize your DM6 M microscope with LIBS technology for chemical particle identification within the analyze process as well as for many more tasks

CONNECT WITH US!

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